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V _{DSS}	Drain to Source Voltage		40	V
V _{GS}	Gate to Source Voltage		±20	V
1	Drain Current - Continuous (V _{GS} =10) (Note 1)	$T_C = 25^{\circ}C$	110	Α
ID	Pulsed Drain Current	T _C = 25°C	See Figure4	A
E _{AS}	Single Pulse Avalanche Energy	(Note 2)	172	mJ
D	Power Dissipation		176	W
P _D	Derate above 25°C		1.18	W/ºC
T _J , T _{STG}	Operating and Storage Temperature		-55 to + 175	°C
$R_{\theta JC}$	Thermal Resistance Junction to Case		0.85	°C/W
$R_{\theta JA}$	Maximum Thermal Resistance Junction to Ambient	(Note 3)	43	°C/W

Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDB9406	FDB9406_F085	TO-263AB	330mm	24mm	800 units

Notes:

1: Current is limited by bondwire configuration. 2: Starting $T_J = 25^{\circ}$ C, L = 0.04mH, I_{AS} = 88A, V_{DD} = 40V during inductor charging and V_{DD} = 0V during time in avalanche 3: R_{0JA} is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. R_{0JC} is guaranteed by design while R_{0JA} is determined by the user's board design. The maximum rating presented here is based on mounting on a 1 in² pad of 2oz copper.

$\begin{array}{c c c c c c c c c } \hline P_{DSS} & Drain to Source Leakage Current & V_{DS}=40V, & T_J=25^{\circ}C & - & - & 1 & \mu^A \\ \hline V_{GS}=0V & T_J=175^{\circ}C(Note 4) & - & - & 1 & m^A \\ \hline V_{GS} & Gate to Source Leakage Current & V_{GS}=\pm 20V & - & - & \pm 100 & n^A \\ \hline Dn Characteristics & & & & & & & & & & & & & \\ \hline Dn Characteristics & & & & & & & & & & & & & & & & & & &$	Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
$\begin{array}{c c c c c c c } \hline V_{DS} & Drain to Source Leakage Current & V_{DS} = 40V, & T_J = 25^\circ C & - & - & 1 & \mu^A \\ \hline V_{GS} & = 0V & T_J = 175^\circ C(Note 4) & - & - & 1 & m^A \\ \hline V_{GS} & = 0V & V_{GS} = \pm 20V & - & - & \pm 100 & n^A \\ \hline On Characteristics & & & & & & \\ \hline On Characteristics & & & & & & & \\ \hline V_{GS(th)} & Gate to Source Threshold Voltage & V_{GS} = V_{DS}, I_D = 250\mu A & 2.0 & 2.83 & 4.0 & V \\ \hline v_{DS(on)} & Drain to Source On Resistance & & & & & & \\ \hline D_{D} = 80A, & & & & & & & \\ \hline I_D = 80A, & & & & & & & & & \\ \hline V_{GS} = 10V & & & & & & & & & & & \\ \hline T_J = 175^\circ C(Note 4) & - & & & & & & & \\ \hline Dynamic Characteristics & & & & & & & \\ \hline C_{iss} & Input Capacitance & & & & & & \\ \hline C_{rss} & Reverse Transfer Capacitance & & & & & \\ \hline R_g & Gate Resistance & & & & & & & & & & \\ \hline R_g & Gate Charge at 10V & & & & & & & & & \\ \hline Q_{GTOT} & Total Gate Charge at 10V & & & & & & & & & & \\ \hline V_{OS} = 0 to 10V & & & & & & & & & & & \\ \hline \hline V_{DD} = 32V & - & & & & & & & & \\ \hline \end{array}$	Off Cha	racteristics					
IDSSDrain to Source Leakage Current $V_{GS} = 0V$ $T_J = 175^{\circ}C(Note 4)$ 1m/AIGSSGate to Source Leakage Current $V_{GS} = \pm 20V$ ± 100 n/AOn Characteristics $V_{GS}(th)$ Gate to Source Threshold Voltage $V_{GS} = V_{DS}$, $I_D = 250\mu A$ 2.02.834.0V $V_{GS}(th)$ Drain to Source On Resistance $I_D = 80A$, $V_{GS} = 10V$ $T_J = 25^{\circ}C$ -1.311.8m/ADynamic Characteristics C_{iss} Input Capacitance C_{rss} $V_{DS} = 25V$, $V_{GS} = 0V$, $f = 1MHz$ -7710-pF C_{rss} Reverse Transfer Capacitance C_{Rg} $Gate Resistance$ $f = 1MHz$ -2.015-pF R_g Gate Resistance $f = 1MHz$ -2.1- Ω Ω $Q_{q(TOT)}$ Total Gate Charge at 10V $V_{GS} = 0$ to 10V $V_{DD} = 32V$ -107138nC	B _{VDSS}	Drain to Source Breakdown Voltage	I _D = 250μA, V _{GS} = 0V	40	-	-	V
SocialV_{GS} = 0VT_J = 175°C(Note 4)1m/dI_{GSS}Gate to Source Leakage Current $V_{GS} = \pm 20V$ ± 100 n/dOn Characteristics $V_{GS}(th)$ Gate to Source Threshold Voltage $V_{GS} = V_{DS}$, $I_D = 250 \mu A$ 2.02.834.0V $r_{DS}(on)$ Drain to Source On Resistance $I_D = 80A$, $V_{GS} = 10V$ $T_J = 25°C$ -1.311.8m/dDynamic Characteristics C_{iss} Input Capacitance $V_{DS} = 25V$, $V_{GS} = 0V$, $f = 1MHz$ -2015-pF C_{rss} Reverse Transfer Capacitance $f = 1MHz$ -2.1- Ω R_g Gate Resistance $f = 1MHz$ -2.1- Ω $Q_q(ToT)$ Total Gate Charge at 10V $V_{GS} = 0$ to 10V $V_{DD} = 32V$ -107138nC	1	Drain to Source Lookage Current	V_{DS} =40V, T_{J} =25°C	-	-	1	μA
On Characteristics $V_{GS(th)}$ Gate to Source Threshold Voltage $V_{GS} = V_{DS}$, $I_D = 250 \mu A$ 2.02.834.0V $r_{DS(on)}$ Drain to Source On Resistance $I_D = 80A$, $V_{GS} = 10V$ $T_J = 25^{\circ}C$ -1.311.8msDynamic Characteristics C_{iss} Input Capacitance $V_{DS} = 25V$, $V_{GS} = 0V$, $f = 1MHz$ -2710-pF C_{rss} Reverse Transfer Capacitance $V_{DS} = 25V$, $V_{GS} = 0V$, $f = 1MHz$ -2015-pF R_g Gate Resistance $f = 1MHz$ -2.1- Ω $Q_{g(ToT)}$ Total Gate Charge at 10V $V_{GS} = 0$ to 10V $V_{DD} = 32V$ -107138nC	DSS	Drain to Source Leakage Current	$V_{GS} = 0V$ $T_J = 175^{\circ}C(Note 4)$	-	-	1	mA
On Characteristics $V_{GS(th)}$ Gate to Source Threshold Voltage $V_{GS} = V_{DS}$, $I_D = 250 \mu A$ 2.02.834.0V $r_{DS(on)}$ Drain to Source On Resistance $I_D = 80A$, $V_{GS} = 10V$ $T_J = 25^{\circ}C$ -1.311.8mgDynamic Characteristics C_{iss} Input Capacitance $V_{DS} = 25V$, $V_{GS} = 0V$, $f = 1MHz$ -2710-pF C_{rss} Reverse Transfer Capacitance $V_{DS} = 25V$, $V_{GS} = 0V$, $f = 1MHz$ -2015-pF R_g Gate Resistance $f = 1MHz$ -2.1- Ω $Q_{q(ToT)}$ Total Gate Charge at 10V $V_{GS} = 0$ to 10V $V_{DD} = 32V$ -107138nC	I _{GSS}	Gate to Source Leakage Current	$V_{GS} = \pm 20V$	-	-	±100	nA
VGS-10VTJ = 175 C(NOLE 4)-2.202.8InstructionDynamic Characteristics C_{iss} Input Capacitance $V_{DS} = 25V, V_{GS} = 0V,$ -7710-pF C_{rss} Reverse Transfer Capacitance $f = 1MHz$ -2015-pF R_g Gate Resistance $f = 1MHz$ -2.1- Ω $Q_{g(ToT)}$ Total Gate Charge at 10V $V_{GS} = 0$ to 10V $V_{DD} = 32V$ -107138nC	r _{DS(on)}	Drain to Source On Resistance			-	-	mΩ
VGS-10VTJ = 175 C(NOLE 4)-2.202.8InstructionDynamic Characteristics C_{iss} Input Capacitance $V_{DS} = 25V, V_{GS} = 0V,$ -7710-pF C_{rss} Reverse Transfer Capacitance $f = 1MHz$ -2015-pF R_g Gate Resistance $f = 1MHz$ -2.1- Ω $Q_{g(ToT)}$ Total Gate Charge at 10V $V_{GS} = 0$ to 10V $V_{DD} = 32V$ -107138nC		Drain to Source On Resistance			-	-	
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $. ,		$V_{GS} = 10V$ $I_{J} = 175^{\circ}C(NOLE 4)$	-	2.20	2.0	11152
$ \begin{array}{c c} C_{oss} & Output Capacitance \\ C_{rss} & Reverse Transfer Capacitance \\ R_g & Gate Resistance \\ Q_{g(ToT)} & Total Gate Charge at 10V \\ \end{array} $	•	Τ			7710	_	nF
C_{rss} Reverse Transfer Capacitance11102-pF R_g Gate Resistancef = 1MHz-2.1- Ω $Q_{g(ToT)}$ Total Gate Charge at 10V $V_{GS} = 0$ to 10V $V_{DD} = 32V$ -107138nC			20 00	-	-	-	
R _g Gate Resistance f = 1MHz - 2.1 - Ω $Q_{g(ToT)}$ Total Gate Charge at 10V $V_{GS} = 0$ to 10V $V_{DD} = 32V$ - 107 138 nC			f = 1MHz	-		-	pF
$V_{g(ToT)}$ Total Gate Charge at 10V $V_{GS} = 0$ to 10V $V_{DD} = 32V$ - 107 138 nC		Gate Resistance	f = 1MHz	-	2.1	-	Ω
	<u> </u>	Total Gate Charge at 10V	$V_{GS} = 0$ to 10V $V_{DD} = 32V$	-	107	138	nC
	Q_(11=)		• <u></u> •	-	14	19	nC

FDB9406_F085 N-Channel Power Trench[®] MOSFET

Switching Characteristics

Gate to Source Gate Charge

Gate to Drain "Miller" Charge

t _{on}	Turn-On Time		-	-	107	ns
t _{d(on)}	Turn-On Delay Time		-	28	-	ns
t _r	Rise Time	V _{DD} = 20V, I _D = 80A,	-	48	-	ns
t _{d(off)}	Turn-Off Delay Time	V_{DD} = 20V, I _D = 80A, V _{GS} = 10V, R _{GEN} = 6Ω	-	50	-	ns
t _f	Fall Time		-	20	-	ns
t _{off}	Turn-Off Time		-	-	100	ns

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nC

nC

Drain-Source Diode Characteristics

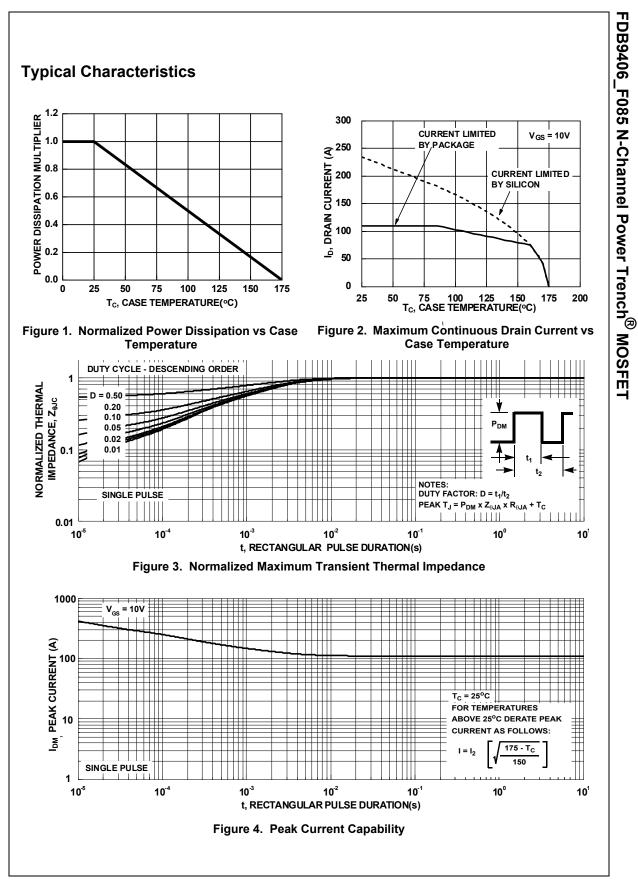
V_{SD}	Source to Drain Diode Voltage	I _{SD} = 80A, V _{GS} = 0V	-	-	1.25	V
T _{rr}	Reverse Recovery Time	I _F = 80A, dI _{SD} /dt = 100A/μs,	-	81	92	ns
Q _{rr}	Reverse Recovery Charge	V _{DD} =32V	-	109	140	nC

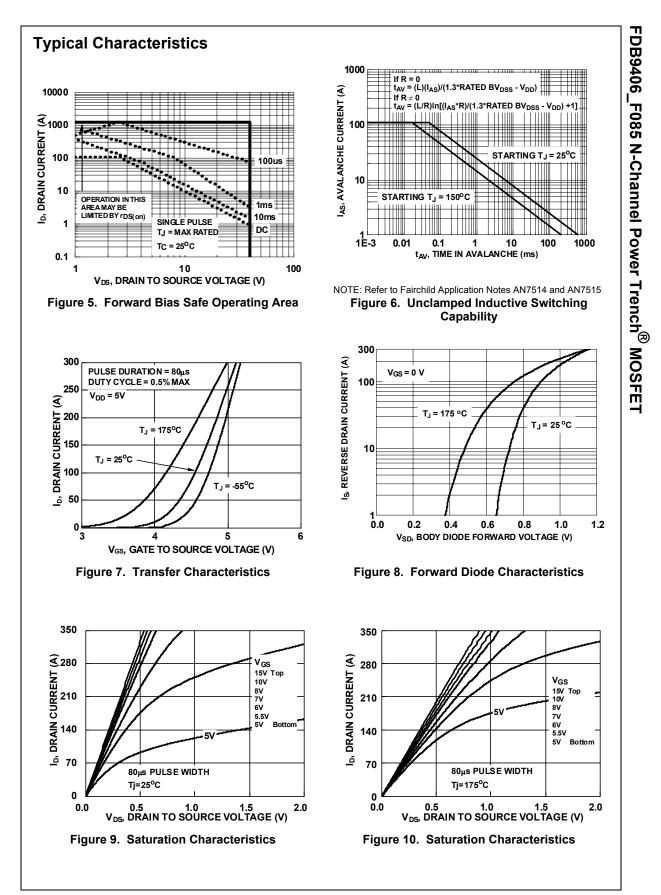
Notes:

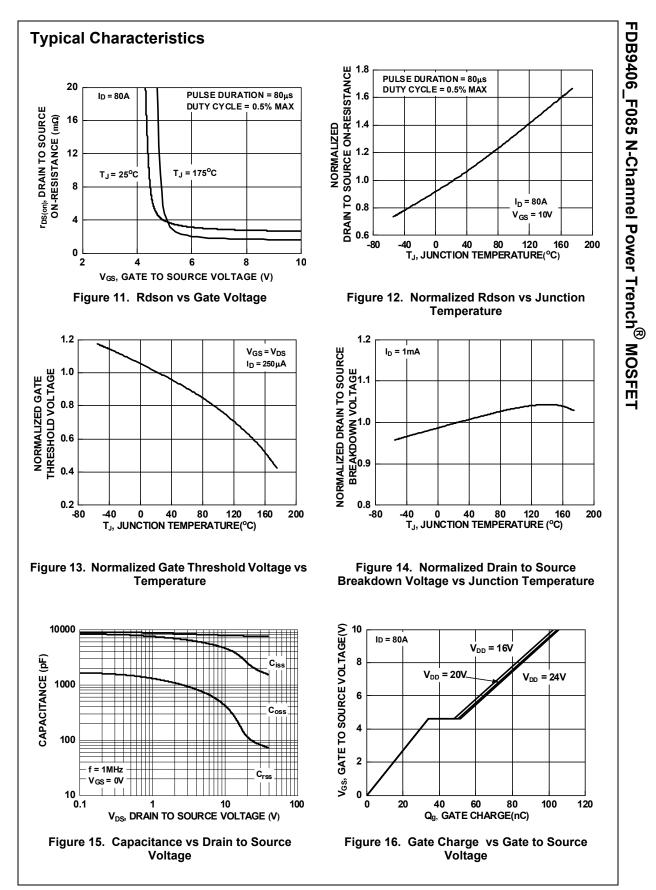
 Q_gs

Q_{gd}

4: The maximum value is specified by design at TJ = 175° C. Product is not tested to this condition in production.







FDB9406_F085 Rev. C1



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